



**FCC Part 1 Subpart I
FCC Part 2 Subpart J
INDUSTRY CANADA RSS 102 ISSUE 5**

RF EXPOSURE REPORT

FOR

WAFERSENSE AUTO MULTI-SENSOR

MODEL NUMBER: AMS-300C, AMS-200C, AMS-150C, AMSR-6025Q

**FCC ID: SPD003
IC: 6210A-003**

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Revision History

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1. ATTESTATION OF TEST RESULTS

COMPANY NAME: CyberOptics Corporation
5900 Golden Hills Drive
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EUT DESCRIPTION: Wafer Sensor

MODEL: AMS-300C, AMS-200C, AMS-150C, AMSR-6025Q

SERIAL NUMBER: N/A

DATE TESTED: 2017-11-16

APPLICABLE STANDARDS	
STANDARD	TEST RESULTS
FCC PART 1 SUBPART I & PART 2 SUBPART J	Pass
INDUSTRY CANADA RSS 102 ISSUE 5	Pass

UL LLC tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL LLC based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

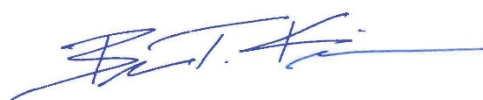
Note: The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL LLC and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL LLC will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the U.S. Government.

Approved & Released
For UL LLC By:



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2. TEST METHODOLOGY

All calculations were made in accordance with FCC Parts 2.1091, 2.1093 and KDB 447498 D01 v06 and IC Safety Code 6, RSS 102 Issue 5.

3. REFERENCES

Output power, Duty cycle and Antenna gain data is excerpted from product documentation provided by the applicant.

4. FACILITIES AND ACCREDITATION

The test sites and measurement facilities used to collect data are located at 12 Laboratory Dr., Research Triangle Park, NC 27709, USA and 2800 Perimeter Park Drive, Suite B, Morrisville, NC 27560, USA

UL LLC (RTP) is accredited by NVLAP, Laboratory Code 200246-0. The full scope of accreditation can be viewed at <http://www.nist.gov/nvlap/>.

5. EUT DESCRIPTION

The EUT is a Bluetooth transceiver used for measuring real-time leveling, vibration and humidity within a Semiconductor Process. The AMS-300C, AMS-200C, AMS-150C, and AMSR-6025Q are all identical except for the housings. The AMS-300C, AMS-200C, AMS-150C all use a carbon housing of varying diameter and the AMSR-6025Q uses a quartz housing.

6. MAXIMUM PERMISSIBLE RF EXPOSURE

6.1. FCC RULES

§1.1310 The criteria listed in Table 1 shall be used to evaluate the environmental impact of human exposure to radio-frequency (RF) radiation as specified in §1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of §2.1093 of this chapter.

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(A) Limits for Occupational/Controlled Exposures				
0.3–3.0	614	1.63	*(100)	6
3.0–30	1842/f	4.89/f	*(900/f ²)	6
30–300	61.4	0.163	1.0	6
300–1500			f/300	6
1500–100,000			5	6
(B) Limits for General Population/Uncontrolled Exposure				
0.3–1.34	614	1.63	*(100)	30
1.34–30	824/f	2.19/f	*(180/f ²)	30

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)—Continued

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
30–300	27.5	0.073	0.2	30
300–1500			f/1500	30
1500–100,000			1.0	30

f = frequency in MHz

* = Plane-wave equivalent power density

NOTE 1 TO TABLE 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure.

NOTE 2 TO TABLE 1: General population/uncontrolled exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.

6.2. IC RULES

IC Safety Code 6 (2015), Section 2.2.2: To ensure compliance with the basic restrictions outlined in Section 2.1, at frequencies between 10 MHz and 300 GHz, the reference levels for electric- and magnetic-field strength and power density must be complied with.

TABLE 5: Reference Levels for Electric Field Strength, Magnetic Field Strength and Power Density in Uncontrolled Environments

Frequency (MHz)	Electric Field Strength (E_{RL}), (V/m, RMS)	Magnetic Field Strength (H_{RL}), (A/m, RMS)	Power Density (S_{RL}), (W/m ²)	Reference Period (minutes)
10–20	27.46	0.0728	2	6
20–48	$58.07 / f^{0.25}$	$0.1540 / f^{0.25}$	$8.944 / f^{0.5}$	6
48–300	22.06	0.05852	1.291	6
300–6000	$3.142 f^{0.3417}$	$0.008335 f^{0.3417}$	$0.02619 f^{0.6834}$	6
6000–15000	61.4	0.163	10	6
15000–150000	61.4	0.163	10	$616000 / f^{1.2}$
150000–300000	$0.158 f^{0.5}$	$4.21 \times 10^{-4} f^{0.5}$	$6.67 \times 10^{-5} f$	$616000 / f^{1.2}$

Frequency, f , is in MHz.

TABLE 6: Reference Levels for Electric Field Strength, Magnetic Field Strength and Power Density in Controlled Environments

Frequency (MHz)	Electric Field Strength (E_{RL}), (V/m, RMS)	Magnetic Field Strength (H_{RL}), (A/m, RMS)	Power Density, (S_{RL}), (W/m ²)	Reference Period (minutes)
10–20	61.4	0.163	10	6
20–48	$129.8 / f^{0.25}$	$0.3444 / f^{0.25}$	$44.72 / f^{0.5}$	6
48–100	49.33	0.1309	6.455	6
100–6000	$15.60 f^{0.25}$	$0.04138 f^{0.25}$	$0.6455 f^{0.5}$	6
6000–15000	137	0.364	50	6
15000–150000	137	0.364	50	$616000 / f^{1.2}$
150000–300000	$0.354 f^{0.5}$	$9.40 \times 10^{-4} f^{0.5}$	$3.33 \times 10^{-4} f$	$616000 / f^{1.2}$

Frequency, f , is in MHz.

NOTES FOR TABLES 5 AND 6:

- For exposures shorter than the reference period, field strengths may exceed the reference levels, provided that the time average of the squared value of the electric or magnetic field strength over any time period equal to the reference period shall not exceed E_{RL}^2 or H_{RL}^2 , respectively. For exposures longer than the reference period, including indefinite exposures, the time average of the squared value of the electric or magnetic field strength over any time period equal to the reference period shall not exceed E_{RL}^2 or H_{RL}^2 , respectively.

6.3. EQUATIONS

POWER DENSITY

Power density is given by:

$$S = \text{EIRP} / (4 * \text{Pi} * D^2)$$

Where

S = Power density in mW/cm²

EIRP = Equivalent Isotropic Radiated Power in mW

D = Separation distance in cm

Power density in units of mW/cm² is converted to units of W/m² by multiplying by 10.

DISTANCE

Distance is given by:

$$D = \text{SQRT} (\text{EIRP} / (4 * \text{Pi} * S))$$

Where

D = Separation distance in cm

EIRP = Equivalent Isotropic Radiated Power in mW

S = Power density in mW/cm²

SOURCE-BASED DUTY CYCLE

Where applicable (for example, multi-slot cell phone applications) a duty cycle factor may be applied.

$$\text{Source-based time-averaged EIRP} = (\text{DC} / 100) * \text{EIRP}$$

Where

DC = Duty Cycle in %, as applicable

EIRP = Equivalent Isotropic Radiated Power in W

MIMO AND COLOCATED TRANSMITTERS (IDENTICAL LIMIT FOR ALL TRANSMITTERS)

For multiple chain devices, and colocated transmitters operating simultaneously in frequency bands where the limit is identical, the total power density is calculated using the total EIRP obtained by summing the EIRP (in linear units) of each transmitter.

$$\text{Total EIRP} = (\text{EIRP1}) + (\text{EIRP2}) + \dots + (\text{EIRPn})$$

where

EIRPx = Source-based time-averaged EIRP of chain x or transmitter x

The total EIRP is then used to calculate the Power Density or the Distance as applicable.

MIMO AND COLOCATED TRANSMITTERS

For multiple colocated transmitters operating simultaneously in frequency bands where different limits apply:

The Power Density at the specified separation distance is calculated for each transmitter chain or transmitter.

The fraction of the exposure limit is calculated for each chain or transmitter as
(Power Density of chain or transmitter) / (Limit applicable to that chain or transmitter).

The fractions are summed.

Compliance is established if the sum of the fractions is less than or equal to one.

6.4. LIMITS AND IC EXEMPTION

INDUSTRY CANADA EXEMPTION

RSS-102 Clause 2.5.2 RF exposure evaluation is required if the separation distance between the user and the device's radiating element is greater than 20 cm, except when the device operates as follows:

- at or above 300 MHz and below 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than $1.31 \times 10^{-2} f^{0.6834}$ W (adjusted for tune-up tolerance), where f is in MHz;

7. RF EXPOSURE RESULTS

In the table(s) below, Power and Gain are entered in units of dBm and dBi respectively and conversions to linear forms are used for the calculations.

Single Chain and non-colocated transmitters								
Band	Mode	Separation Distance (cm)	Output AVG Power (dBm)	Antenna Gain (dBi)	Duty Cycle (%)	EIRP (mW)	FCC Power Density (mW/cm ²)	IC Power Density (W/m ²)
2.4 GHz	Bluetooth	20	12.00	-0.40	100.0	14.5	0.003	0.03

The device operates above 1.5 GHz with a maximum EIRP less than or equal to 5 Watts as a mobile device with a minimum separation distance of 20 cm, therefore it is exempt from routine RF Exposure Evaluation under RSS-102.

Notes:

- 1) For MPE the new KDB 447498 requires the calculations to use the maximum rated power; that power should be declared by the manufacturer, and should not be lower than the measured power. If the power has a tolerance then we also need to check that the measured power is within the tolerance.
- 2) The manufacturer configures output power so that the maximum power, after accounting for manufacturing tolerances, will never exceed the maximum power level measured.
- 3) The antenna gain in the tables above is the maximum antenna gain among various channels within the specified band.

END OF REPORT